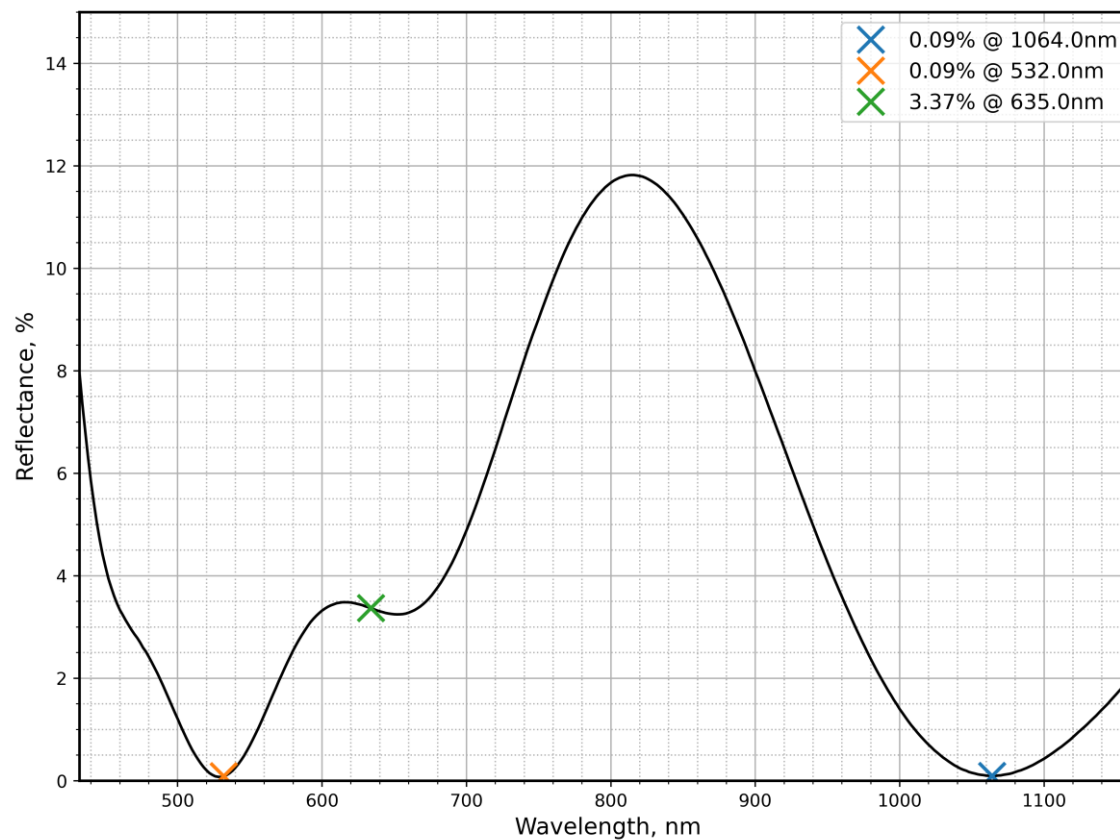


S1:Ru<0.15%@ 1064 + Ru<0.15%@ 532 nm + AR<10% @ 635 nm, AOI=0-2°
S2:Ru<0.15%@ 1064 + Ru<0.15%@ 532 nm + AR<10% @ 635 nm, AOI=0-2°



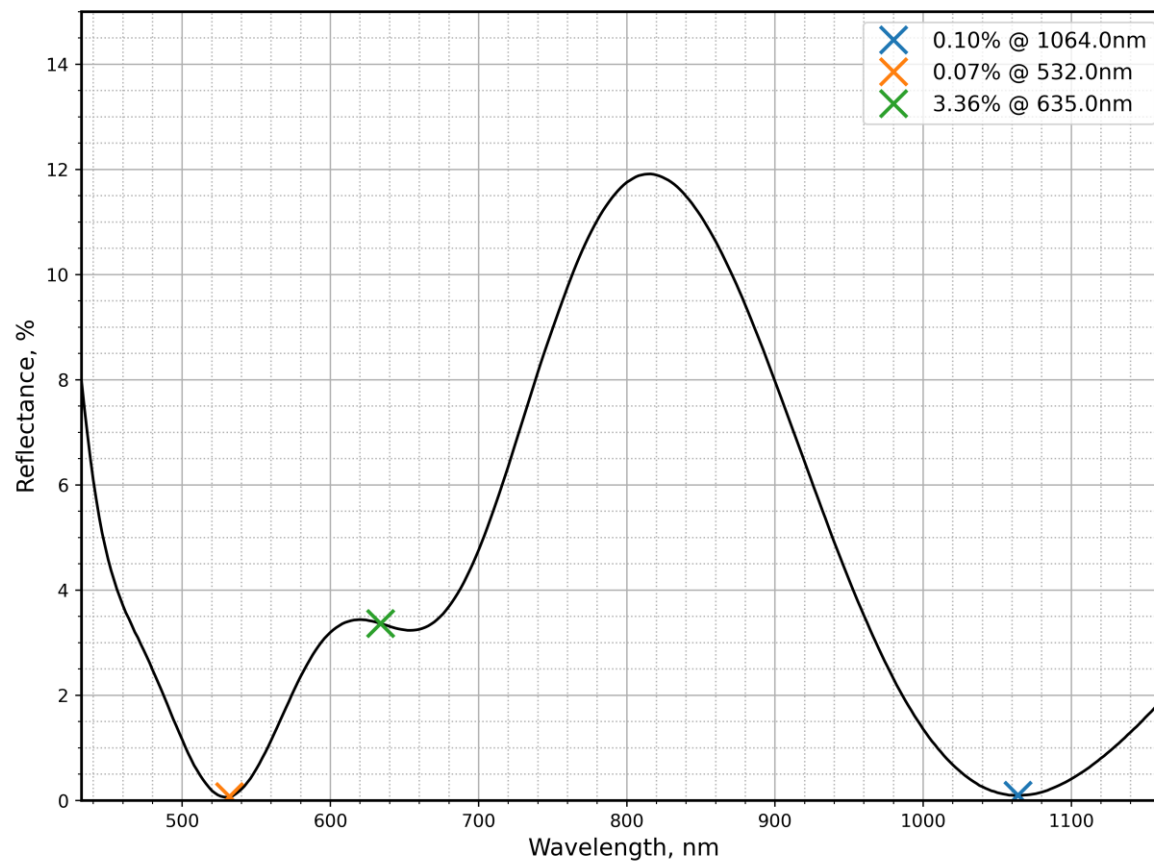
PO11228 Ra i8

Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.1%

S1:Ru<0.15%@ 1064 + Ru<0.15%@ 532 nm + AR<10% @ 635 nm, AOI=0-2°
S2:Ru<0.15%@ 1064 + Ru<0.15%@ 532 nm + AR<10% @ 635 nm, AOI=0-2°



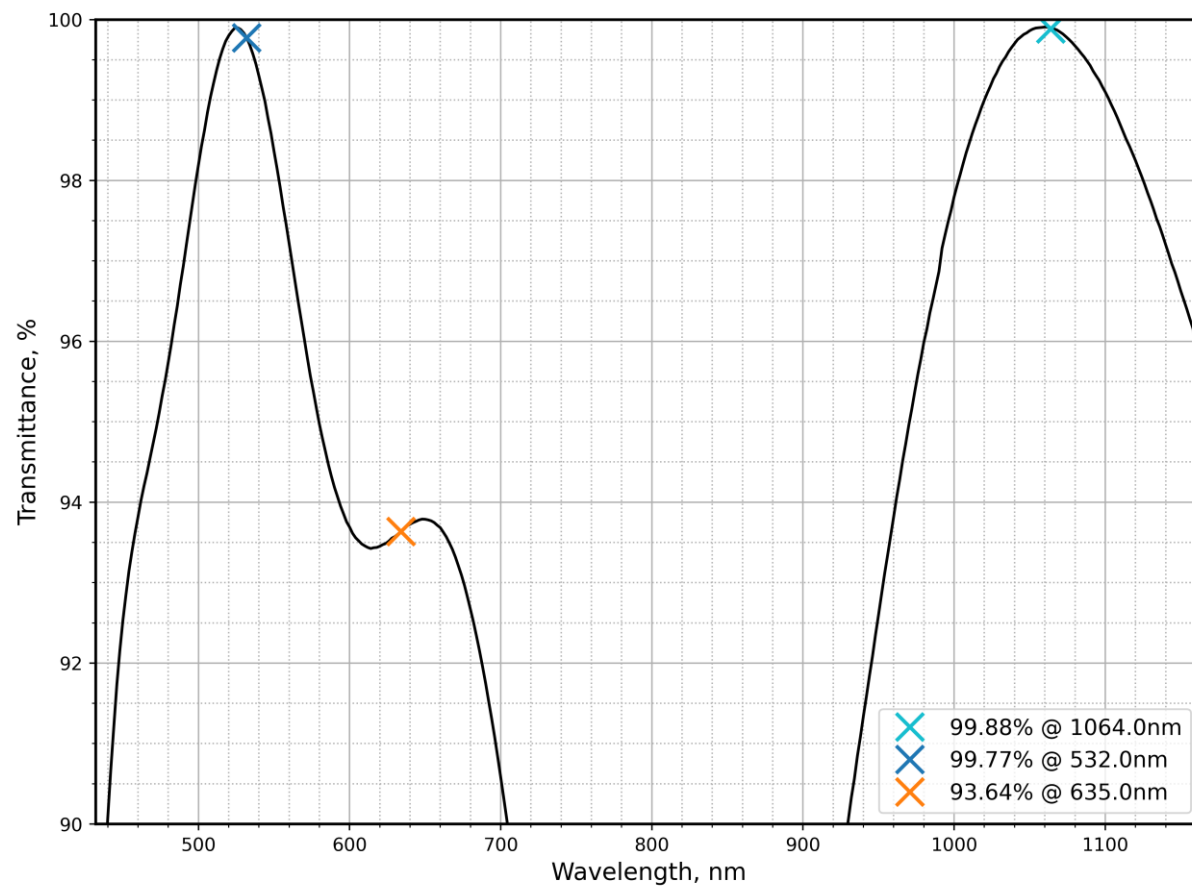
PO11228 Ra i8

Fig. 2.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.1%

S1:Ru<0.15%@ 1064 + Ru<0.15%@ 532 nm + AR<10% @ 635 nm, AOI=0-2°
S2:Ru<0.15%@ 1064 + Ru<0.15%@ 532 nm + AR<10% @ 635 nm, AOI=0-2°



PO11228 Ta i0

Fig. 3.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.1%